



Sheet 1 of 2

FORM PTO-1449  
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
NIT-163-02SERIAL NO.  
10/075,283LIST OF DOCUMENTS CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
M. IWAYAMA et alFILING DATE  
February 15, 2002GROUP  
2175

## U.S. PATENT DOCUMENTS

* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA	5,590,319	12/31/96	Cohen et al			
	AB	5,987,460	11/1999	Niwa et al			
	AC	5,926,811	07/1999	Miller et al			
	AD	5,870,740	02/1999	Miller et al			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL	64-74210	03/20/89	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AM	93/37499	08/27/98	WO PCT			<input type="checkbox"/>	<input type="checkbox"/>
	AN	10-74210	03/17/98	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
	AO	11-85786	03/30/99	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
	AP	10-254887	09/25/98	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

AR		B. Velez et al, "Fast and Effective Query Refinement", Annual International ACM-SIGIR Conference on Research and Development in Information Retrieval,
		US, New York, NY, July 27, 1997, pp. 6-15.
AS		
AT		

EXAMINER \_\_\_\_\_ DATE CONSIDERED \_\_\_\_\_

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Sheet 2 of 2

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AF						
AG						
AH						
AI						
AJ						
AK						

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**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AL	8-287103	11/01/96	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
AM	9-62693	03/07/97	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
AN						<input type="checkbox"/>	<input type="checkbox"/>
AO						<input type="checkbox"/>	<input type="checkbox"/>
AP						<input type="checkbox"/>	<input type="checkbox"/>

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)**

EXAMINER	AR	
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